Search Notes



Application/Control No.	
10/786 072	

Applicant(s)/Patent under Reexamination
ISHII ET AL.
Art Unit

Patrick A. Darno

Examiner

SEARCHED				
Class	Subclass	Date	Examiner	
709	229	11/18/2005	PAD	
709	225	11/18/2005	PAD	
709	218	11/18/2005	PAD	
709	104	11/18/2005	PAD	
455	410	11/18/2005	PAD	
		-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u>]</u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST .	11/18/2005	PAD	
PLUS	11/18/2005	PAD	
IEEE DATABASE	11/19/2005	PAD	